

Application/Control No.	Applicant(s)/Patent under Reexamination
09/778,154	YOO, SEO HONG
Examiner	Art Unit

1639

Mark L. Shibuya

SEARCHED				
Class	Subclass	Date	Examiner	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
Updated	5/14/2006	MS
Discussed new matter objections to the specification with QAS C. Low and SPE A. Wang	5/12/2006	ms
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